



## Description

The XPX16P20XS uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

$V_{DS} = -20V, ID = -16A$

$R_{DS(ON)} = 10m\Omega$  (typ) @  $V_{GS} = -4.5V$

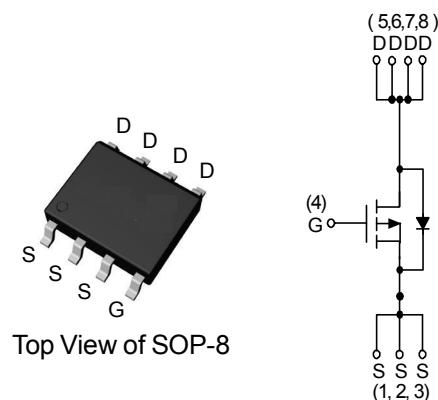
$R_{DS(ON)} = 13m\Omega$  (typ) @  $V_{GS} = -2.5V$

## General Features

- High density cell design for ultra low  $R_{dson}$
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high  $E_{AS}$
- Excellent package for good heat dissipation

## Application

- Load switch
- Battery protection



P-Channel MOSFET

## Absolute Maximum Ratings ( $T_A = 25^\circ C$ Unless Otherwise Noted)

Symbol	Parameter	Rating	Unit
$V_{DSS}$	Drain-Source Voltage	-20	V
$V_{GSS}$	Gate-Source Voltage	$\pm 12$	
$I_D^a$	Continuous Drain Current ( $V_{GS} = -4.5V$ )	$T_A = 25^\circ C$	A
		$T_A = 100^\circ C$	
$I_{DM}^a$	Pulsed Drain Current ( $V_{GS} = -4.5V$ )	-44 *	A
$I_S^a$	Diode Continuous Forward Current	-10	
$T_J$	Maximum Junction Temperature	150	$^\circ C$
$I_{AS}^d$	Avalanche Current, Single pulse	$L = 0.5mH$	A
$E_{AS}^d$	Avalanche Energy, Single pulse	$L = 0.5mH$	mJ
$T_{STG}$	Storage Temperature Range	-55 to 150	$^\circ C$
$P_D^a$	Maximum Power Dissipation	$T_A = 25^\circ C$	W
		$T_A = 70^\circ C$	
$R_{\theta JA}^{a,b}$	Thermal Resistance-Junction to Ambient	$t \leq 10s$	$^\circ C/W$
		Steady State	
$R_{\theta JL}^c$	Thermal Resistance-Junction to Case	24	$^\circ C/W$

Note \* : Package limited.

Note a : Surface Mounted on 1in<sup>2</sup> pad area,  $t \leq 10sec$ .

Note b : Maximum under Steady State conditions is 75  $^\circ C/W$ .

Note c : The power dissipation  $P_D$  is based on  $T_{J(MAX)} = 150^\circ C$ , and it is useful for reducing junction-to-case thermal resistance ( $R_{\theta JC}$ ) when additional heat sink is used.

Note d : UIS tested and pulse width limited by maximum junction temperature 150oC (initial temperature  $T_j = 25oC$ ).

## **Electrical Characteristics** ( $T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

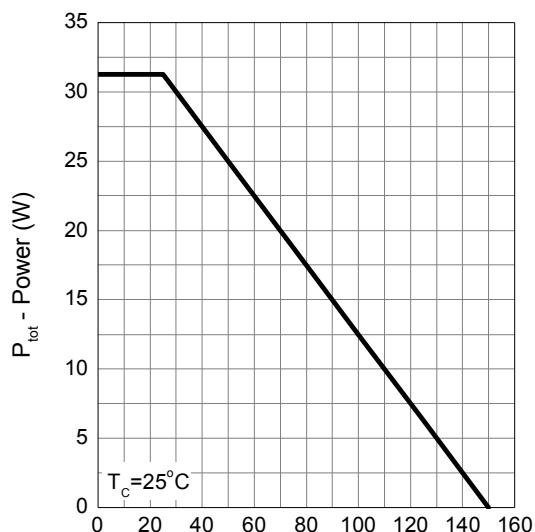
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Characteristics</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{DS}}=-250\mu\text{A}$	-20	-	-	V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{\text{DS}}=-16\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-1	$\mu\text{A}$
		$T_J=85^\circ\text{C}$	-	-	-30	
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{DS}}=-250\mu\text{A}$	-0.5	-	-1	V
$I_{\text{GSS}}$	Gate Leakage Current	$V_{\text{GS}}=\pm 12\text{V}, V_{\text{DS}}=0\text{V}$	-	-	$\pm 10$	$\mu\text{A}$
$R_{\text{DS(ON)}}^{\text{e}}$	Drain-Source On-state Resistance	$V_{\text{GS}}=-4.5\text{V}, I_{\text{DS}}=-16\text{A}$	-	10	13	$\text{m}\Omega$
		$V_{\text{GS}}=-2.5\text{V}, I_{\text{DS}}=-6\text{A}$	-	13	18	
		$V_{\text{GS}}=-1.8\text{V}, I_{\text{DS}}=-1\text{A}$	-	20	25	
<b>Diode Characteristics</b>						
$V_{\text{SD}}^{\text{e}}$	Diode Forward Voltage	$I_{\text{SD}}=-1\text{A}, V_{\text{GS}}=0\text{V}$	-	-0.7	-1	V
$t_{\text{rr}}^{\text{f}}$	Reverse Recovery Time	$I_{\text{SD}}=-11\text{A}, dI_{\text{SD}}/dt=100\text{A}/\mu\text{s}$	-	63	-	ns
$Q_{\text{rr}}^{\text{f}}$	Reverse Recovery Charge		-	54	-	nC
<b>Dynamic Characteristics</b> <sup>f</sup>						
$C_{\text{iss}}$	Input Capacitance	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=-10\text{V}, \text{Frequency}=1.0\text{MHz}$	-	1620	-	$\text{pF}$
$C_{\text{oss}}$	Output Capacitance		-	320	-	
$C_{\text{rss}}$	Reverse Transfer Capacitance		-	290	-	
$t_{\text{d(ON)}}$	Turn-on Delay Time	$V_{\text{DD}}=-10\text{V}, R_L=10\Omega, I_{\text{DS}}=-1\text{A}, V_{\text{GEN}}=-4.5\text{V}, R_G=6\Omega$	-	9	-	$\text{ns}$
$t_r$	Turn-on Rise Time		-	13	-	
$t_{\text{d(OFF)}}$	Turn-off Delay Time		-	26	-	
$t_f$	Turn-off Fall Time		-	167	-	
<b>Gate Charge Characteristics</b> <sup>f</sup>						
$Q_g$	Total Gate Charge	$V_{\text{DS}}=-10\text{V}, V_{\text{GS}}=-4.5\text{V}, I_{\text{DS}}=-11\text{A}$	-	25	-	$\text{nC}$
$Q_{\text{gs}}$	Gate-Source Charge		-	1.6	-	
$Q_{\text{gd}}$	Gate-Drain Charge		-	11	-	

Note e : Pulse test; pulse width $\leq 300\mu\text{s}$ , duty cycle $\leq 2\%$ .

Note f : Guaranteed by design, not subject to production testing.

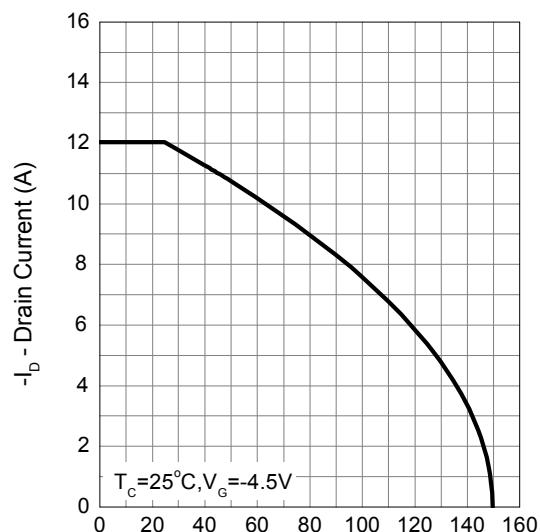
## Typical Operating Characteristics

**Power Dissipation**



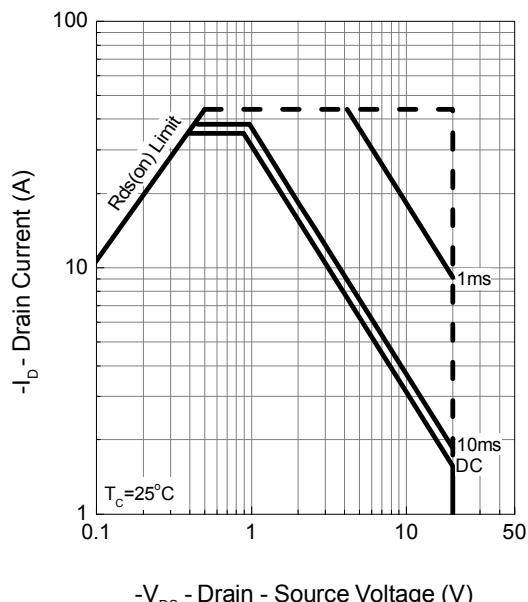
$T_j$  - Junction Temperature ( $^\circ\text{C}$ )

**Drain Current**



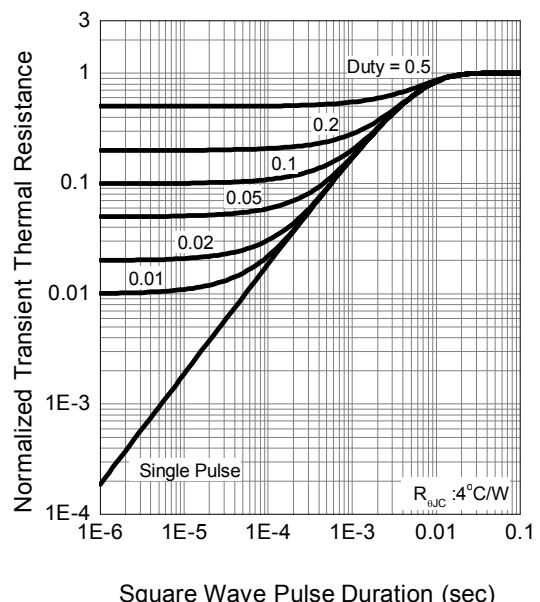
$T_j$  - Junction Temperature ( $^\circ\text{C}$ )

**Safe Operation Area**



$-V_{DS}$  - Drain - Source Voltage (V)

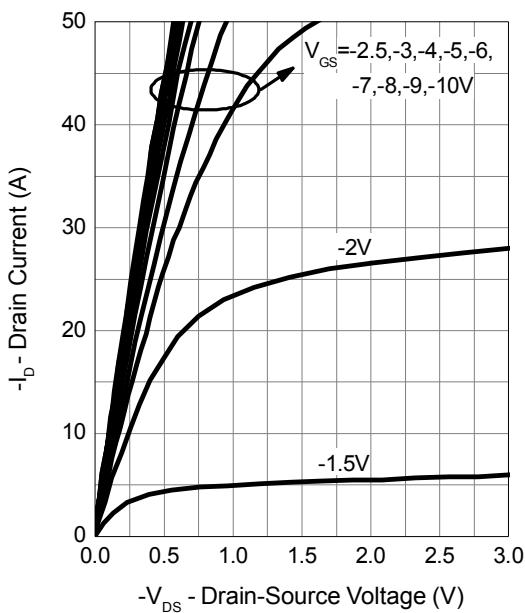
**Thermal Transient Impedance**



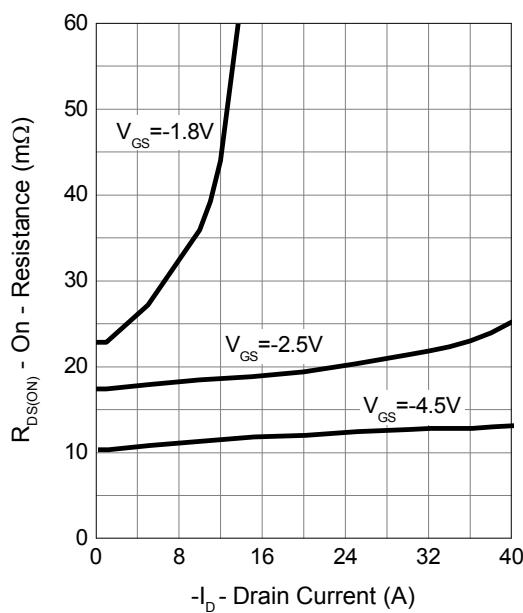
Square Wave Pulse Duration (sec)

## Typical Operating Characteristics (Cont.)

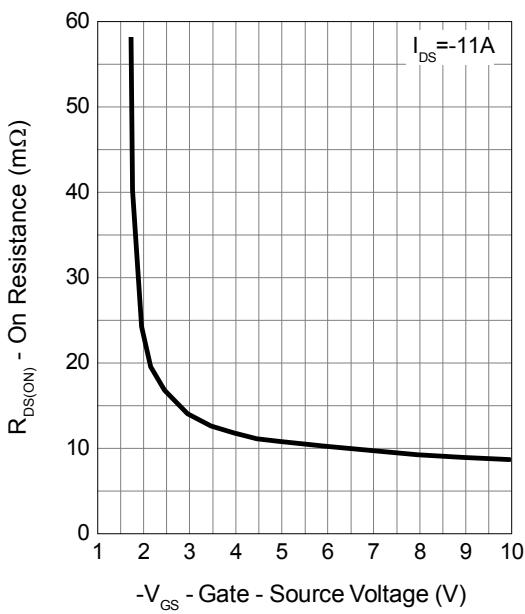
**Output Characteristics**



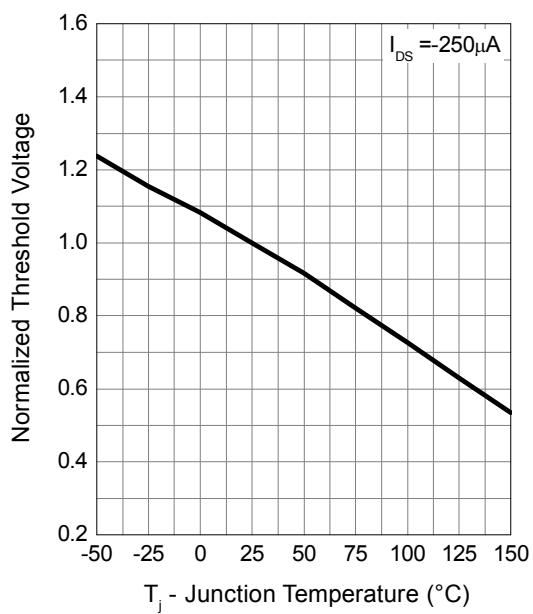
**Drain-Source On Resistance**



**Gate-Source On Resistance**

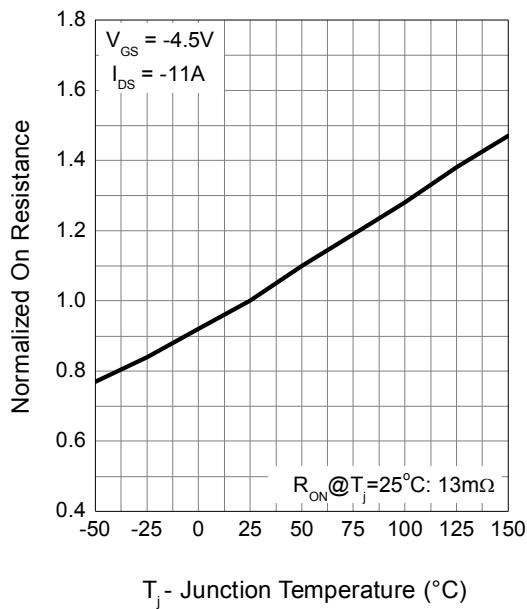


**Gate Threshold Voltage**

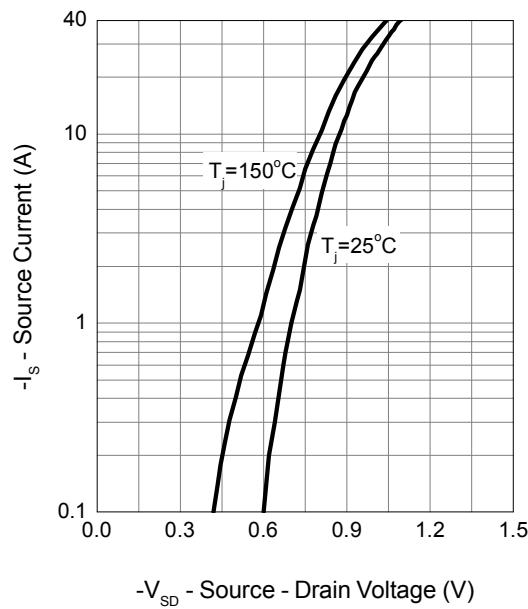


## Typical Operating Characteristics (Cont.)

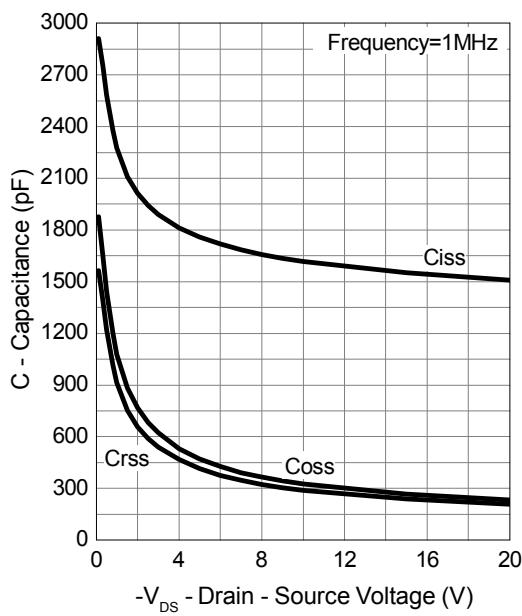
**Drain-Source On Resistance**



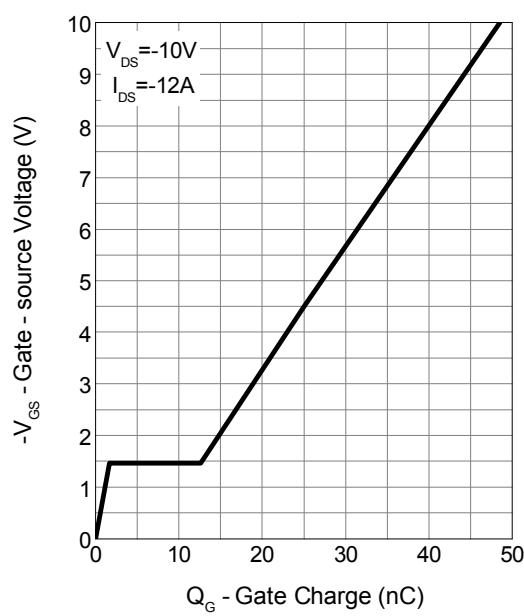
**Source-Drain Diode Forward**



**Capacitance**

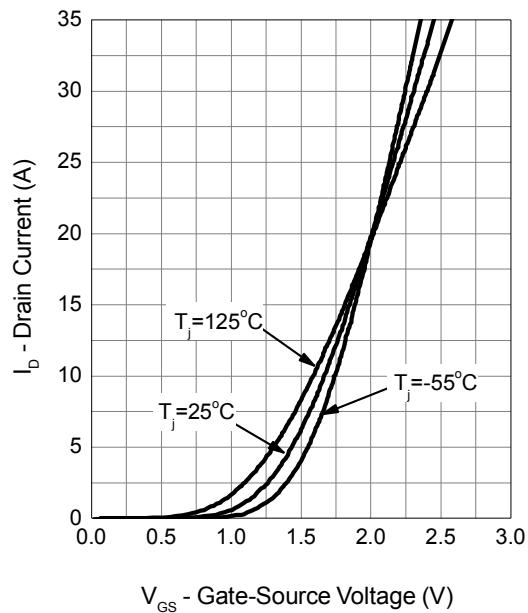


**Gate Charge**

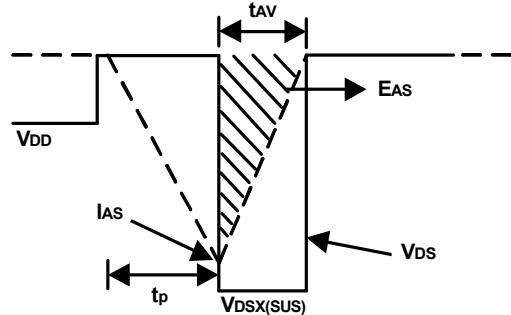
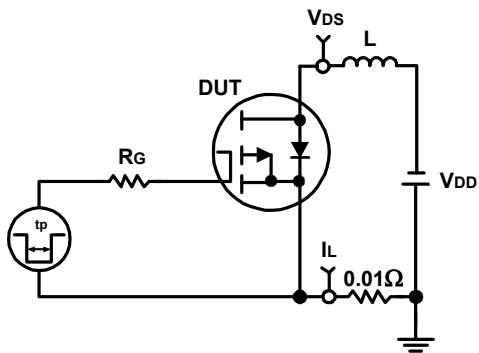


## Typical Operating Characteristics (Cont.)

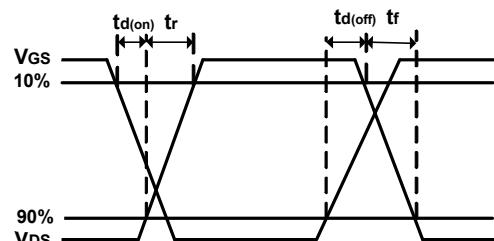
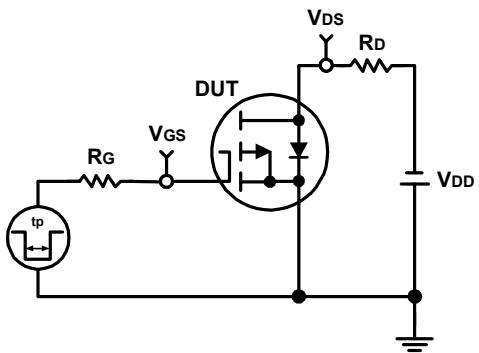
Transfer Characteristics



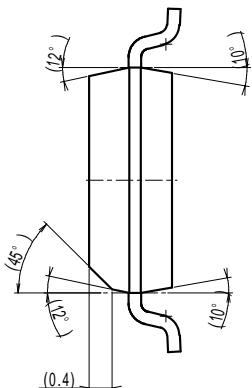
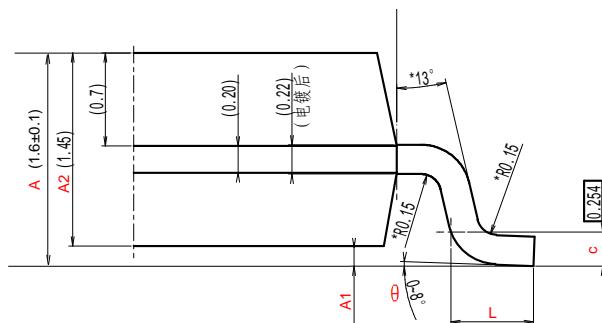
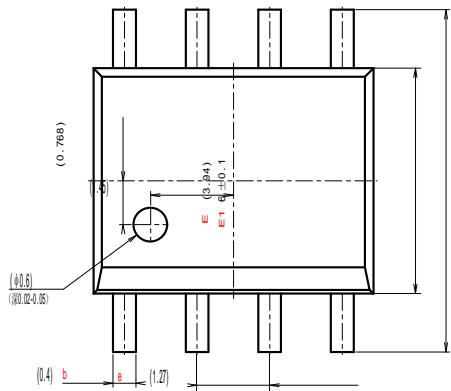
## Avalanche Test Circuit and Waveforms



## Switching Time Test Circuit and Waveforms



## SOP8 PACKAGE OUTLINE



字符	Dimension millimeters		
	Min	Standard	Max
A	1.500	1.600	1.700
A1	0.040	0.080	0.150
A2	1.350	1.450	1.550
b	0.300	0.400	0.500
c	0.220	0.254	0.280
D	4.800	4.900	5.000
E	3.840	3.940	4.040
E1	5.900	6.000	6.100
e		1.27 (BSC)	
L	0.400	0.550	0.700
θ	0°		8°

